# E·XFL

#### Intel - 5SGXEA7N3F40C4N Datasheet



Welcome to E-XFL.COM

#### Understanding <u>Embedded - FPGAs (Field</u> <u>Programmable Gate Array)</u>

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

#### **Applications of Embedded - FPGAs**

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

#### Details

Product Status	Obsolete
Number of LABs/CLBs	234720
Number of Logic Elements/Cells	622000
Total RAM Bits	51200000
Number of I/O	600
Number of Gates	-
Voltage - Supply	0.82V ~ 0.88V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	1517-BBGA, FCBGA
Supplier Device Package	1517-FBGA (40x40)
Purchase URL	https://www.e-xfl.com/product-detail/intel/5sgxea7n3f40c4n

Email: info@E-XFL.COM

Address: Room A, 16/F, Full Win Commercial Centre, 573 Nathan Road, Mongkok, Hong Kong

Symbol	Description	Minimum	Maximum	Unit
V <sub>CCD_FPLL</sub>	PLL digital power supply	-0.5	1.8	V
V <sub>CCA_FPLL</sub>	PLL analog power supply	-0.5	3.4	V
VI	DC input voltage	-0.5	3.8	V
TJ	Operating junction temperature	-55	125	°C
T <sub>STG</sub>	Storage temperature (No bias)	-65	150	°C
I <sub>OUT</sub>	DC output current per pin	-25	40	mA

Table 3. Absolute Maximum Ratings for Stratix V Devices (Part 2 of 2)

Table 4 lists the absolute conditions for the transceiver power supply for Stratix V GX, GS, and GT devices.

Table 4. Transceiver Power Supply Absolute Conditions for Stratix V GX, GS, and GT Devices

Symbol	Description	Devices	Minimum	Maximum	Unit
V <sub>CCA_GXBL</sub>	Transceiver channel PLL power supply (left side)	GX, GS, GT	-0.5	3.75	V
V <sub>CCA_GXBR</sub>	Transceiver channel PLL power supply (right side)	GX, GS	-0.5	3.75	V
V <sub>CCA_GTBR</sub>	Transceiver channel PLL power supply (right side)	GT	-0.5	3.75	V
V <sub>CCHIP_L</sub>	Transceiver hard IP power supply (left side)	GX, GS, GT	-0.5	1.35	V
V <sub>CCHIP_R</sub>	Transceiver hard IP power supply (right side)	GX, GS, GT	-0.5	1.35	V
V <sub>CCHSSI_L</sub>	Transceiver PCS power supply (left side)	GX, GS, GT	-0.5	1.35	V
V <sub>CCHSSI_R</sub>	Transceiver PCS power supply (right side)	GX, GS, GT	-0.5	1.35	V
V <sub>CCR_GXBL</sub>	Receiver analog power supply (left side)	GX, GS, GT	-0.5	1.35	V
V <sub>CCR_GXBR</sub>	Receiver analog power supply (right side)	GX, GS, GT	-0.5	1.35	V
V <sub>CCR_GTBR</sub>	Receiver analog power supply for GT channels (right side)	GT	-0.5	1.35	V
V <sub>CCT_GXBL</sub>	Transmitter analog power supply (left side)	GX, GS, GT	-0.5	1.35	V
V <sub>CCT_GXBR</sub>	Transmitter analog power supply (right side)	GX, GS, GT	-0.5	1.35	V
V <sub>CCT_GTBR</sub>	Transmitter analog power supply for GT channels (right side)	GT	-0.5	1.35	V
V <sub>CCL_GTBR</sub>	Transmitter clock network power supply (right side)	GT	-0.5	1.35	V
V <sub>CCH_GXBL</sub>	Transmitter output buffer power supply (left side)	GX, GS, GT	-0.5	1.8	V
V <sub>CCH_GXBR</sub>	Transmitter output buffer power supply (right side)	GX, GS, GT	-0.5	1.8	V

#### **Maximum Allowed Overshoot and Undershoot Voltage**

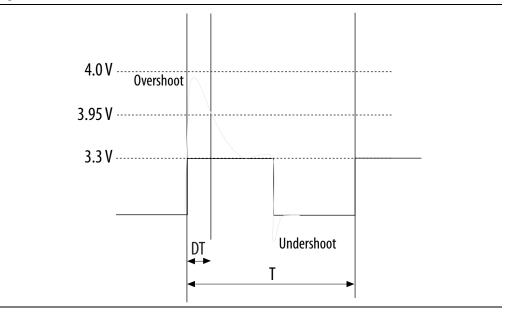
During transitions, input signals may overshoot to the voltage shown in Table 5 and undershoot to -2.0 V for input currents less than 100 mA and periods shorter than 20 ns.

Table 5 lists the maximum allowed input overshoot voltage and the duration of the overshoot voltage as a percentage of device lifetime. The maximum allowed overshoot duration is specified as a percentage of high time over the lifetime of the device. A DC signal is equivalent to 100% of the duty cycle. For example, a signal that overshoots to 3.95 V can be at 3.95 V for only ~21% over the lifetime of the device; for a device lifetime of 10 years, the overshoot duration amounts to ~2 years.

abie 5. Maximum Anowed Overshoot During Industrions									
Symbol	Description	Condition (V)	Overshoot Duration as % @ T <sub>J</sub> = 100°C	Unit					
		3.8	100	%					
		3.85	64	%					
		3.9	36	%					
		3.95	21	%					
Vi (AC)	AC input voltage	4	12	%					
		4.05	7	%					
		4.1	4	%					
		4.15	2	%					
		4.2	1	%					

Table 5. Maximum Allowed Overshoot During Transitions

#### Figure 1. Stratix V Device Overshoot Duration



				Calibration Accuracy					
Symbol	Description	Conditions	C1	C2,12	C3,I3, I3YY	C4,14	Unit		
50-Ω R <sub>S</sub>	Internal series termination with calibration (50- $\Omega$ setting)	V <sub>CCI0</sub> = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%		
34-Ω and 40-Ω R <sub>S</sub>	Internal series termination with calibration (34- $\Omega$ and 40- $\Omega$ setting)	V <sub>CCI0</sub> = 1.5, 1.35, 1.25, 1.2 V	±15	±15	±15	±15	%		
48-Ω, 60-Ω, 80-Ω, and 240-Ω R <sub>S</sub>	Internal series termination with calibration (48- $\Omega$ , 60- $\Omega$ , 80- $\Omega$ , and 240- $\Omega$ setting)	V <sub>CCI0</sub> = 1.2 V	±15	±15	±15	±15	%		
50-Ω R <sub>T</sub>	Internal parallel termination with calibration (50-Ω setting)	V <sub>CCIO</sub> = 2.5, 1.8, 1.5, 1.2 V	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%		
20- $Ω$ , 30- $Ω$ , 40- $Ω$ ,60- $Ω$ , and 120- $Ω$ R <sub>T</sub>	Internal parallel termination with calibration ( $20 \cdot \Omega$ , $30 \cdot \Omega$ , $40 \cdot \Omega$ , $60 \cdot \Omega$ , and $120 \cdot \Omega$ setting)	V <sub>CCI0</sub> = 1.5, 1.35, 1.25 V	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%		
60-Ω and 120-Ω $R_T$	Internal parallel termination with calibration (60- $\Omega$ and 120- $\Omega$ setting)	V <sub>CCI0</sub> = 1.2	-10 to +40	-10 to +40	-10 to +40	-10 to +40	%		
$\begin{array}{l} \textbf{25-}\Omega\\ \textbf{R}_{S\_left\_shift} \end{array}$	Internal left shift series termination with calibration (25- $\Omega$ R <sub>S_left_shift</sub> setting)	V <sub>CCI0</sub> = 3.0, 2.5, 1.8, 1.5, 1.2 V	±15	±15	±15	±15	%		

Table 11. OCT Calibration Accurat	y Specifications for Stratix V Devices <sup>(1)</sup> (	(Part 2 of 2)
-----------------------------------	---	---------------

#### Note to Table 11:

(1) OCT calibration accuracy is valid at the time of calibration only.

Table 12 lists the Stratix V OCT without calibration resistance to PVT changes.

			<b>Resistance Tolerance</b>					
Symbol	Description	nination C1 C2,I2 C3, I3, I3, I3, I3, I3, I3, I3, I3, I3, I		C4, I4	Unit			
25-Ω R, 50-Ω R <sub>S</sub>	Internal series termination without calibration (25- $\Omega$ setting)	$V_{CCIO} = 3.0$ and 2.5 V	±30	±30	±40	±40	%	
25-Ω R <sub>S</sub>	Internal series termination without calibration (25-Ω setting)	$V_{CCIO} = 1.8$ and 1.5 V	±30	±30	±40	±40	%	
25-Ω R <sub>S</sub>	Internal series termination without calibration (25-Ω setting)	V <sub>CCI0</sub> = 1.2 V	±35	±35	±50	±50	%	

#### **Internal Weak Pull-Up Resistor**

Table 16 lists the weak pull-up resistor values for Stratix V devices.

Symbol	Description	V <sub>CCIO</sub> Conditions (V) <sup>(3)</sup>	Value <sup>(4)</sup>	Unit
		3.0 ±5%	25	kΩ
		2.5 ±5%	25	kΩ
	Value of the I/O pin pull-up resistor before	1.8 ±5%	25	kΩ
R <sub>PU</sub>	and during configuration, as well as user mode if you enable the programmable	1.5 ±5%	25	kΩ
	pull-up resistor option.	1.35 ±5%	25	kΩ
		1.25 ±5%	25	kΩ
		1.2 ±5%	25	kΩ

Table 16. Internal Weak Pull-Up Resistor for Stratix V Devices (1), (2)

Notes to Table 16:

(1) All I/O pins have an option to enable the weak pull-up resistor except the configuration, test, and JTAG pins.

(2) The internal weak pull-down feature is only available for the JTAG TCK pin. The typical value for this internal weak pull-down resistor is approximately 25 k $\Omega$ .

- (3) The pin pull-up resistance values may be lower if an external source drives the pin higher than V<sub>CCIO</sub>.
- (4) These specifications are valid with a  $\pm 10\%$  tolerance to cover changes over PVT.

### I/O Standard Specifications

Table 17 through Table 22 list the input voltage (V<sub>IH</sub> and V<sub>IL</sub>), output voltage (V<sub>OH</sub> and V<sub>OL</sub>), and current drive characteristics (I<sub>OH</sub> and I<sub>OL</sub>) for various I/O standards supported by Stratix V devices. These tables also show the Stratix V device family I/O standard specifications. The V<sub>OL</sub> and V<sub>OH</sub> values are valid at the corresponding I<sub>OH</sub> and I<sub>OL</sub>, respectively.

For an explanation of the terms used in Table 17 through Table 22, refer to "Glossary" on page 65. For tolerance calculations across all SSTL and HSTL I/O standards, refer to Altera knowledge base solution rd07262012\_486.

I/O		V <sub>ccio</sub> (V)		V	L (V)	VIH	(V)	V <sub>OL</sub> (V)	V <sub>OH</sub> (V)	IOL	I <sub>oh</sub>
Standard	Min	Тур	Max	Min	Max	Min	Max	Max	Min	(mĀ)	(mÅ)
LVTTL	2.85	3	3.15	-0.3	0.8	1.7	3.6	0.4	2.4	2	-2
LVCMOS	2.85	3	3.15	-0.3	0.8	1.7	3.6	0.2	$V_{CCI0} - 0.2$	0.1	-0.1
2.5 V	2.375	2.5	2.625	-0.3	0.7	1.7	3.6	0.4	2	1	-1
1.8 V	1.71	1.8	1.89	-0.3	0.35 * V <sub>CCI0</sub>	0.65 * V <sub>CCI0</sub>	V <sub>CCI0</sub> + 0.3	0.45	V <sub>CCI0</sub> – 0.45	2	-2
1.5 V	1.425	1.5	1.575	-0.3	0.35 * V <sub>CCI0</sub>	0.65 * V <sub>CCI0</sub>	V <sub>CCI0</sub> + 0.3	0.25 * V <sub>CCI0</sub>	0.75 * V <sub>CCIO</sub>	2	-2
1.2 V	1.14	1.2	1.26	-0.3	0.35 * V <sub>CCI0</sub>	0.65 * V <sub>CCIO</sub>	V <sub>CCI0</sub> + 0.3	0.25 * V <sub>CCI0</sub>	0.75 * V <sub>CCI0</sub>	2	-2

Table 17. Single-Ended I/O Standards for Stratix V Devices

- You typically use the interactive Excel-based Early Power Estimator before designing the FPGA to get a magnitude estimate of the device power. The Quartus II PowerPlay Power Analyzer provides better quality estimates based on the specifics of the design after you complete place-and-route. The PowerPlay Power Analyzer can apply a combination of user-entered, simulation-derived, and estimated signal activities that, when combined with detailed circuit models, yields very accurate power estimates.
- **\*** For more information about power estimation tools, refer to the *PowerPlay Early Power Estimator User Guide* and the *PowerPlay Power Analysis* chapter in the *Quartus II Handbook*.

## Table 23. Transceiver Specifications for Stratix V GX and GS Devices <sup>(1)</sup> (Part 6 of 7)

Symbol/ Description	Conditions	Trai	isceive Grade	r Speed 1	Trar	nsceiver Speed Grade 2		Transceiver Speed Grade 3			Unit
Description		Min	Тур	Max	Min	Тур	Max	Min	Тур	Max	
Inter-transceiver block transmitter channel-to- channel skew	xN PMA bonded mode			500	_		500	_		500	ps
CMU PLL											
Supported Data Range	_	600		12500	600	_	12500	600	_	8500/ 10312.5 (24)	Mbps
t <sub>pll_powerdown</sub> <sup>(15)</sup>	_	1		—	1	—	—	1	—	—	μs
t <sub>pll_lock</sub> (16)	_		_	10	—	_	10	—	—	10	μs
ATX PLL	1										
	VCO post-divider L=2	8000		14100	8000	_	12500	8000	_	8500/ 10312.5 (24)	Mbps
Current and Date	L=4	4000	_	7050	4000	_	6600	4000	—	6600	Mbps
Supported Data Rate Range	L=8	2000	_	3525	2000	_	3300	2000	_	3300	Mbps
	L=8, Local/Central Clock Divider =2	1000	_	1762.5	1000		1762.5	1000		1762.5	Mbps
t <sub>pll_powerdown</sub> (15)	_	1		_	1			1	—	_	μs
t <sub>pll_lock</sub> <sup>(16)</sup>	—			10	—	—	10	—	—	10	μs
fPLL	•			•			•		•	•	
Supported Data Range	_	600	_	3250/ 3125 <sup>(25)</sup>	600	_	3250/ 3125 <sup>(25)</sup>	600	_	3250/ 3125 <sup>(25)</sup>	Mbps
t <sub>pll_powerdown</sub> <sup>(15)</sup>	_	1	_	_	1	_	—	1	—	—	μs

Mada (2)	Transceiver	PMA Width	20	20	16	16	10	10	8	8
Mode <sup>(2)</sup>	Speed Grade	PCS/Core Width	40	20	32	16	20	10	16	8
	1	C1, C2, C2L, I2, I2L core speed grade	12.2	11.4	9.76	9.12	6.5	5.8	5.2	4.72
2 FIFO 3	0	C1, C2, C2L, I2, I2L core speed grade	12.2	11.4	9.76	9.12	6.5	5.8	5.2	4.72
	2	C3, I3, I3L core speed grade	9.8	9.0	7.84	7.2	5.3	4.7	4.24	3.76
		C1, C2, C2L, I2, I2L core speed grade	8.5	8.5	8.5	8.5	6.5	5.8	5.2	4.72
	2	I3YY core speed grade	10.3125	10.3125	7.84	7.2	5.3	4.7	4.24	3.76
	C3, I3, I3L core speed grade	8.5	8.5	7.84	7.2	5.3	4.7	4.24	3.76	
		C4, I4 core speed grade	8.5	8.2	7.04	6.56	4.8	4.2	3.84	3.44
	1	C1, C2, C2L, I2, I2L core speed grade	12.2	11.4	9.76	9.12	6.1	5.7	4.88	4.56
	2	C1, C2, C2L, I2, I2L core speed grade	12.2	11.4	9.76	9.12	6.1	5.7	4.88	4.56
	2	C3, I3, I3L core speed grade	9.8	9.0	7.92	7.2	4.9	4.5	3.96	3.6
Register		C1, C2, C2L, I2, I2L core speed grade	10.3125	10.3125	10.3125	10.3125	6.1	5.7	4.88	4.56
	2	I3YY core speed grade	10.3125	10.3125	7.92	7.2	4.9	4.5	3.96	3.6
	3	C3, I3, I3L core speed grade	8.5	8.5	7.92	7.2	4.9	4.5	3.96	3.6
		C4, I4 core speed grade	8.5	8.2	7.04	6.56	4.4	4.1	3.52	3.28

Table 25 shows the approximate maximum data rate using the standard PCS.

Table 25. Stratix V Standard PCS Approximate Maximum Date Rate (1), (3)

Notes to Table 25:

(1) The maximum data rate is in Gbps.

(2) The Phase Compensation FIFO can be configured in FIFO mode or register mode. In the FIFO mode, the pointers are not fixed, and the latency can vary. In the register mode the pointers are fixed for low latency.

(3) The maximum data rate is also constrained by the transceiver speed grade. Refer to Table 1 for the transceiver speed grade.

Symbol/	Conditions	:	Transceive Speed Grade			r 3	Unit			
Description		Min	Тур	Max	Min	Тур	Max			
Reference Clock										
Supported I/O Standards	Dedicated reference clock pin	1.2-V PCN	/IL, 1.4-V PC	ML, 1.5-V P	CML, 2.5-V and HCSL	PCML, Diffe	rential LVPE	ECL, LVDS		
	RX reference clock pin		1.4-V PCML, 1.5-V PCML, 2.5-V PCML, LVPECL, and LVDS							
Input Reference Clock Frequency (CMU PLL) <sup>(6)</sup>	_	40	_	710	40	_	710	MHz		
Input Reference Clock Frequency (ATX PLL) <sup>(6)</sup>	_	100	-	710	100	_	710	MHz		
Rise time	20% to 80%		_	400		—	400			
Fall time	80% to 20%			400	—		400	ps		
Duty cycle	—	45		55	45		55	%		
Spread-spectrum modulating clock frequency	PCI Express (PCIe)	30	_	33	30	_	33	kHz		
Spread-spectrum downspread	PCle	_	0 to -0.5		_	0 to -0.5	_	%		
On-chip termination resistors <sup>(19)</sup>	_	_	100	_	_	100	_	Ω		
Absolute V <sub>MAX</sub> <sup>(3)</sup>	Dedicated reference clock pin		_	1.6	_	_	1.6	V		
	RX reference clock pin	_	_	1.2	_	_	1.2			
Absolute V <sub>MIN</sub>	—	-0.4	—	—	-0.4	—	—	V		
Peak-to-peak differential input voltage	_	200	_	1600	200	_	1600	mV		
V <sub>ICM</sub> (AC coupled)	Dedicated reference clock pin		1050/1000 (	2)		2)	mV			
	RX reference clock pin	1	.0/0.9/0.85 (	22)	1.	V				
V <sub>ICM</sub> (DC coupled)	HCSL I/O standard for PCIe reference clock	250	_	550	250	_	550	mV		

#### Table 28. Transceiver Specifications for Stratix V GT Devices (Part 1 of 5) <sup>(1)</sup>

Figure 4 shows the differential transmitter output waveform.



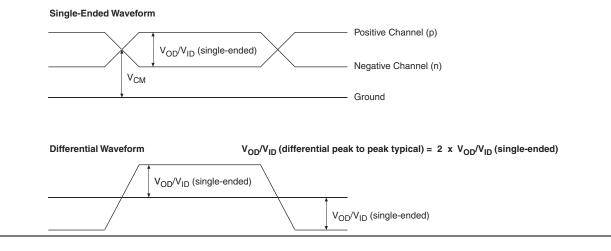


Figure 5 shows the Stratix V AC gain curves for GT channels.

Figure 5. AC Gain Curves for GT Channels

## **PLL Specifications**

Table 31 lists the Stratix V PLL specifications when operating in both the commercial junction temperature range (0° to  $85^{\circ}$ C) and the industrial junction temperature range (-40° to  $100^{\circ}$ C).

Table 31. PLL Specifications for Stratix V Devices (Part 1 of 3)

Symbol	Parameter	Min	Тур	Max	Unit
	Input clock frequency (C1, C2, C2L, I2, and I2L speed grades)	5	_	800 (1)	MHz
f <sub>IN</sub>	Input clock frequency (C3, I3, I3L, and I3YY speed grades)	5	_	800 (1)	MHz
	Input clock frequency (C4, I4 speed grades)	5	_	650 <sup>(1)</sup>	MHz
f <sub>INPFD</sub>	Input frequency to the PFD	5	—	325	MHz
f <sub>finpfd</sub>	Fractional Input clock frequency to the PFD	50	_	160	MHz
	PLL VCO operating range (C1, C2, C2L, I2, I2L speed grades)	600	_	1600	MHz
f <sub>VCO</sub>	PLL VCO operating range (C3, I3, I3L, I3YY speed grades)	600	_	1600	MHz
	PLL VCO operating range (C4, I4 speed grades)	600	—	1300	MHz
t <sub>einduty</sub>	Input clock or external feedback clock input duty cycle	40		60	%
	Output frequency for an internal global or regional clock (C1, C2, C2L, I2, I2L speed grades)	—	_	717 <sup>(2)</sup>	MHz
f <sub>оит</sub>	Output frequency for an internal global or regional clock (C3, I3, I3L speed grades)	_	_	650 <sup>(2)</sup>	MHz
	Output frequency for an internal global or regional clock (C4, I4 speed grades)	_	_	580 <sup>(2)</sup>	MHz
	Output frequency for an external clock output (C1, C2, C2L, I2, I2L speed grades)	_	_	800 (2)	MHz
f <sub>out_ext</sub>	Output frequency for an external clock output (C3, I3, I3L speed grades)	_	_	667 <sup>(2)</sup>	MHz
	Output frequency for an external clock output (C4, I4 speed grades)	_	_	553 <sup>(2)</sup>	MHz
t <sub>outduty</sub>	Duty cycle for a dedicated external clock output (when set to <b>50%</b> )	45	50	55	%
t <sub>FCOMP</sub>	External feedback clock compensation time	_	—	10	ns
f <sub>dyconfigclk</sub>	Dynamic Configuration Clock used for <code>mgmt_clk</code> and <code>scanclk</code>	_	_	100	MHz
t <sub>LOCK</sub>	Time required to lock from the end-of-device configuration or deassertion of areset	_	_	1	ms
t <sub>olock</sub>	Time required to lock dynamically (after switchover or reconfiguring any non-post-scale counters/delays)	_	_	1	ms
	PLL closed-loop low bandwidth		0.3	—	MHz
f <sub>CLBW</sub>	PLL closed-loop medium bandwidth	_	1.5		MHz
	PLL closed-loop high bandwidth (7)		4	—	MHz
t <sub>PLL_PSERR</sub>	Accuracy of PLL phase shift			±50	ps
t <sub>areset</sub>	Minimum pulse width on the areset signal	10	_		ns

Symbol	Parameter	Min	Тур	Max	Unit
+ (3) (4)	Input clock cycle-to-cycle jitter ( $f_{REF} \ge 100 \text{ MHz}$ )	_	—	0.15	UI (p-p)
t <sub>INCCJ</sub> <sup>(3),</sup> <sup>(4)</sup>	Input clock cycle-to-cycle jitter (f <sub>REF</sub> < 100 MHz)	-750	_	+750	ps (p-p)
t	Period Jitter for dedicated clock output (f_{OUT} $\geq$ 100 MHz)	_	_	175 <sup>(1)</sup>	ps (p-p)
t <sub>outpj_dc</sub> <sup>(5)</sup>	Period Jitter for dedicated clock output (f <sub>OUT</sub> < 100 MHz)	_		17.5 <sup>(1)</sup>	mUI (p-p)
+ (5)	Period Jitter for dedicated clock output in fractional PLL ( $f_{0UT} \geq 100 \mbox{ MHz})$	_	_	250 <sup>(11)</sup> , 175 <sup>(12)</sup>	ps (p-p)
t <sub>foutpj_dc</sub> <sup>(5)</sup>	Period Jitter for dedicated clock output in fractional PLL (f <sub>OUT</sub> < 100 MHz)	_	_	25 <sup>(11)</sup> , 17.5 <sup>(12)</sup>	mUI (p-p)
+	Cycle-to-Cycle Jitter for a dedicated clock output ( $f_{OUT} \ge 100 \text{ MHz}$ )	_	_	175	ps (p-p)
t <sub>outccj_dc</sub> <sup>(5)</sup>	Cycle-to-Cycle Jitter for a dedicated clock output (f <sub>0UT</sub> < 100 MHz)	_	_	17.5	mUI (p-p)
<b>+</b> <i>(5)</i>	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL (f_{OUT} $\geq$ 100 MHz)	_	_	250 <sup>(11)</sup> , 175 <sup>(12)</sup>	ps (p-p)
t <sub>FOUTCCJ_DC</sub> <sup>(5)</sup>	Cycle-to-cycle Jitter for a dedicated clock output in fractional PLL ( $f_{OUT} < 100 \text{ MHz}$ )+	_	_	25 <sup>(11)</sup> , 17.5 <sup>(12)</sup>	mUI (p-p)
t <sub>outpj_10</sub> (5),	Period Jitter for a clock output on a regular I/O in integer PLL (f_{OUT} $\geq$ 100 MHz)	_	_	600	ps (p-p)
(8)	Period Jitter for a clock output on a regular I/O (f <sub>OUT</sub> < 100 MHz)	_	_	60	mUI (p-p)
t <sub>FOUTPJ_IO</sub> (5),	Period Jitter for a clock output on a regular I/O in fractional PLL ( $f_{OUT} \ge 100 \text{ MHz}$ )	_	_	600 (10)	ps (p-p)
(8), (11)	Period Jitter for a clock output on a regular I/O in fractional PLL (f <sub>OUT</sub> < 100 MHz)	_	_	60 <sup>(10)</sup>	mUI (p-p)
t <sub>outccj_lo</sub> (5),	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL (f_{OUT} $\geq$ 100 MHz)	_	_	600	ps (p-p)
(8)	Cycle-to-cycle Jitter for a clock output on a regular I/O in integer PLL ( $f_{OUT}$ < 100 MHz)	_	_	60 <sup>(10)</sup>	mUI (p-p)
t <sub>foutccj_10</sub> <sup>(5),</sup>	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ( $f_{0UT} \geq 100 \mbox{ MHz})$	_	_	600 <sup>(10)</sup>	ps (p-p)
(8), (11)	Cycle-to-cycle Jitter for a clock output on a regular I/O in fractional PLL ( $f_{OUT} < 100 \text{ MHz}$ )	_	_	60	mUI (p-p)
t <sub>casc_outpj_dc</sub>	Period Jitter for a dedicated clock output in cascaded PLLs (f_{0UT} $\geq$ 100 MHz)		_	175	ps (p-p)
(5), (6)	Period Jitter for a dedicated clock output in cascaded PLLs (f <sub>OUT</sub> < 100 MHz)		_	17.5	mUI (p-p)
f <sub>DRIFT</sub>	Frequency drift after PFDENA is disabled for a duration of 100 $\mu s$	_	_	±10	%
dK <sub>BIT</sub>	Bit number of Delta Sigma Modulator (DSM)	8	24	32	Bits
k <sub>value</sub>	Numerator of Fraction	128	8388608	2147483648	

Table 31. PLL Specifications for Stratix V Devices (Part 2 of 3)

		Resour	ces Used			Pe	erforman	ce			Unit
Memory	Mode	ALUTS	Memory	C1	C2, C2L	C3	C4	12, 12L	13, 13L, 13YY	14	
	Single-port, all supported widths	0	1	700	700	650	550	700	500	450	MHz
	Simple dual-port, all supported widths	0	1	700	700	650	550	700	500	450	MHz
	Simple dual-port with the read-during-write option set to <b>Old Data</b> , all supported widths	0	1	525	525	455	400	525	455	400	MHz
M20K Block	Simple dual-port with ECC enabled, 512 × 32	0	1	450	450	400	350	450	400	350	MHz
	Simple dual-port with ECC and optional pipeline registers enabled, 512 × 32	0	1	600	600	500	450	600	500	450	MHz
	True dual port, all supported widths	0	1	700	700	650	550	700	500	450	MHz
	ROM, all supported widths	0	1	700	700	650	550	700	500	450	MHz

#### Table 33. Memory Block Performance Specifications for Stratix V Devices <sup>(1), (2)</sup> (Part 2 of 2)

#### Notes to Table 33:

(1) To achieve the maximum memory block performance, use a memory block clock that comes through global clock routing from an on-chip PLL set to **50**% output duty cycle. Use the Quartus II software to report timing for this and other memory block clocking schemes.

(2) When you use the error detection cyclical redundancy check (CRC) feature, there is no degradation in F<sub>MAX</sub>.

(3) The F<sub>MAX</sub> specification is only achievable with Fitter options, MLAB Implementation In 16-Bit Deep Mode enabled.

## **Temperature Sensing Diode Specifications**

Table 34 lists the internal TSD specification.

#### **Table 34. Internal Temperature Sensing Diode Specification**

Temperature Range	Accuracy Calibrated Sampling Option		Sampling Rate	Conversion Time	Resolution	Minimum Resolution with no Missing Codes
–40°C to 100°C	±8°C	No	1 MHz, 500 KHz	< 100 ms	8 bits	8 bits

Table 35 lists the specifications for the Stratix V external temperature sensing diode.

Description	Min	Тур	Max	Unit
I <sub>bias</sub> , diode source current	8	—	200	μA
V <sub>bias,</sub> voltage across diode	0.3	—	0.9	V
Series resistance		—	< 1	Ω
Diode ideality factor	1.006	1.008	1.010	

Speed Grade	Min	Max	Unit
C4,I4	8	16	ps

#### Table 40. DQS Phase Offset Delay Per Setting for Stratix V Devices <sup>(1), (2)</sup> (Part 2 of 2)

#### Notes to Table 40:

(1) The typical value equals the average of the minimum and maximum values.

(2) The delay settings are linear with a cumulative delay variation of 40 ps for all speed grades. For example, when using a -2 speed grade and applying a 10-phase offset setting to a 90° phase shift at 400 MHz, the expected average cumulative delay is [625 ps + (10 × 10 ps) ± 20 ps] = 725 ps ± 20 ps.

Table 41 lists the DQS phase shift error for Stratix V devices.

Table 41. DQS Phase Shift Error Specification for DLL-Delayed Clock (t<sub>DQS\_PSERR</sub>) for Stratix V Devices <sup>(1)</sup>

Number of DQS Delay Buffers	C1	C1 C2, C2L, I2, I2L C3		C4,14	Unit
1	28	28	30	32	ps
2	56	56	60	64	ps
3	84	84	90	96	ps
4	112	112	120	128	ps

Notes to Table 41:

(1) This error specification is the absolute maximum and minimum error. For example, skew on three DQS delay buffers in a -2 speed grade is  $\pm 78$  ps or  $\pm 39$  ps.

Table 42 lists the memory output clock jitter specifications for Stratix V devices.

Clock Network	Parameter	Symbol	C1		C2, C2L, I2, I2L		C3, I3, I3L, I3YY		C4,14		Unit
NELWUIK		-	Min	Max	Min	Max	Min	Max	Min	Max	
	Clock period jitter	t <sub>JIT(per)</sub>	-50	50	-50	50	-55	55	-55	55	ps
Regional	Cycle-to-cycle period jitter	$t_{\rm JIT(cc)}$	-100	100	-100	100	-110	110	-110	110	ps
	Duty cycle jitter	$t_{JIT(duty)}$	-50	50	-50	50	-82.5	82.5	-82.5	82.5	ps
	Clock period jitter	t <sub>JIT(per)</sub>	-75	75	-75	75	-82.5	82.5	-82.5	82.5	ps
Global	Cycle-to-cycle period jitter	$t_{\text{JIT(cc)}}$	-150	150	-150	150	-165	165	-165	165	ps
	Duty cycle jitter	$t_{JIT(duty)}$	-75	75	-75	75	-90	90	-90	90	ps

## **Duty Cycle Distortion (DCD) Specifications**

Table 44 lists the worst-case DCD for Stratix V devices.

#### Table 44. Worst-Case DCD on Stratix V I/O Pins (1)

Symbol	C	1	C2, C2	L, 12, 12L	C3, I3, I3L, I3YY		C4,14		Unit	
	Min	Max	Min	Max	Min	Max	Min	Max		
Output Duty Cycle	45	55	45	55	45	55	45	55	%	

#### Note to Table 44:

(1) The DCD numbers do not cover the core clock network.

# **Configuration Specification**

## **POR Delay Specification**

Power-on reset (POR) delay is defined as the delay between the time when all the power supplies monitored by the POR circuitry reach the minimum recommended operating voltage to the time when the nSTATUS is released high and your device is ready to begin configuration.



For more information about the POR delay, refer to the *Hot Socketing and Power-On Reset in Stratix V Devices* chapter.

Table 45 lists the fast and standard POR delay specification.

#### Table 45. Fast and Standard POR Delay Specification (1)

POR Delay	Minimum	Maximum
Fast	4 ms	12 ms
Standard	100 ms	300 ms

#### Note to Table 45:

(1) You can select the POR delay based on the MSEL settings as described in the MSEL Pin Settings section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.

## **JTAG Configuration Specifications**

Table 46 lists the JTAG timing parameters and values for Stratix V devices.

Table 46. JTAG Timing Parameters and Values for Stratix V Devices

Symbol	Description	Min	Max	Unit
t <sub>JCP</sub>	TCK clock period <sup>(2)</sup>	30	—	ns
t <sub>JCP</sub>	TCK clock period <sup>(2)</sup>	167	—	ns
t <sub>JCH</sub>	TCK clock high time <sup>(2)</sup>	14	—	ns
t <sub>JCL</sub>	TCK clock low time <sup>(2)</sup>	14	—	ns
t <sub>JPSU (TDI)</sub>	TDI JTAG port setup time	2	—	ns
t <sub>JPSU (TMS)</sub>	TMS JTAG port setup time	3	—	ns

Family	Device	Package	Configuration .rbf Size (bits)	IOCSR .rbf Size (bits) <sup>(4), (5)</sup>
Stratix V E <sup>(1)</sup>	5SEE9	—	342,742,976	700,888
	5SEEB	_	342,742,976	700,888

#### Table 47. Uncompressed .rbf Sizes for Stratix V Devices

#### Notes to Table 47:

(1) Stratix V E devices do not have PCI Express® (PCIe®) hard IP. Stratix V E devices do not support the CvP configuration scheme.

(2) 36-transceiver devices.

(3) 24-transceiver devices.

(4) File size for the periphery image.

(5) The IOCSR .rbf size is specifically for the CvP feature.

Use the data in Table 47 to estimate the file size before design compilation. Different configuration file formats, such as a hexadecimal (.hex) or tabular text file (.ttf) format, have different file sizes. For the different types of configuration file and file sizes, refer to the Quartus II software. However, for a specific version of the Quartus II software, any design targeted for the same device has the same uncompressed configuration file size. If you are using compression, the file size can vary after each compilation because the compression ratio depends on your design.

• For more information about setting device configuration options, refer to *Configuration, Design Security, and Remote System Upgrades in Stratix V Devices.* For creating configuration files, refer to the *Quartus II Help.* 

Table 48 lists the minimum configuration time estimates for Stratix V devices.

Variant	Member	Active Serial <sup>(1)</sup>			Fast Passive Parallel <sup>(2)</sup>		
	Member Code	Width	DCLK (MHz)	Min Config Time (s)	Width	DCLK (MHz)	Min Config Time (s)
	A3	4	100	0.534	32	100	0.067
	AS	4	100	0.344	32	100	0.043
	A4	4	100	0.534	32	100	0.067
	A5	4	100	0.675	32	100	0.084
	A7	4	100	0.675	32	100	0.084
GX	A9	4	100	0.857	32	100	0.107
	AB	4	100	0.857	32	100	0.107
	B5	4	100	0.676	32	100	0.085
	B6	4	100	0.676	32	100	0.085
	B9	4	100	0.857	32	100	0.107
	BB	4	100	0.857	32	100	0.107
ст	C5	4	100	0.675	32	100	0.084
GT	C7	4	100	0.675	32	100	0.084

Page 60

Table 51 lists the timing parameters for Stratix V devices for FPP configuration when the DCLK-to-DATA[] ratio is more than 1.

Symbol	Parameter	Minimum	Maximum	Units
t <sub>CF2CD</sub>	nCONFIG low to CONF_DONE low	—	600	ns
t <sub>CF2ST0</sub>	nCONFIG low to nSTATUS low	—	600	ns
t <sub>CFG</sub>	nCONFIG low pulse width	2	_	μS
t <sub>STATUS</sub>	nSTATUS low pulse width	268	1,506 <sup>(2)</sup>	μS
t <sub>CF2ST1</sub>	nCONFIG high to nSTATUS high	—	1,506 <sup>(2)</sup>	μS
t <sub>CF2CK</sub> <sup>(5)</sup>	nCONFIG high to first rising edge on DCLK	1,506	_	μS
t <sub>ST2CK</sub> <sup>(5)</sup>	nSTATUS high to first rising edge of DCLK	2	—	μS
t <sub>DSU</sub>	DATA [] setup time before rising edge on DCLK	5.5		ns
t <sub>DH</sub>	DATA [] hold time after rising edge on DCLK	N-1/f <sub>DCLK</sub> <sup>(5)</sup>		S
t <sub>CH</sub>	DCLK high time	$0.45  imes 1/f_{MAX}$		S
t <sub>CL</sub>	DCLK low time	$0.45\times1/f_{MAX}$		S
t <sub>CLK</sub>	DCLK period	1/f <sub>MAX</sub>		S
f	DCLK frequency (FPP ×8/×16)	—	125	MHz
f <sub>MAX</sub>	DCLK frequency (FPP ×32)	—	100	MHz
t <sub>R</sub>	Input rise time	—	40	ns
t <sub>F</sub>	Input fall time	—	40	ns
t <sub>CD2UM</sub>	CONF_DONE high to user mode <sup>(3)</sup>	175	437	μS
t <sub>CD2CU</sub>	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	_	_
t <sub>CD2UMC</sub>	CONF_DONE high to user mode with CLKUSR option on	$t_{CD2CU}$ + (8576 × CLKUSR period) <sup>(4)</sup>	_	_

#### Notes to Table 51:

- (1) Use these timing parameters when you use the decompression and design security features.
- (2) You can obtain this value if you do not delay configuration by extending the nCONFIG or nSTATUS low pulse width.
- (3) The minimum and maximum numbers apply only if you use the internal oscillator as the clock source for initializing the device.
- (4) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on these pins, refer to the Initialization section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.
- (5) N is the  ${\tt DCLK}\mbox{-to-DATA}$  ratio and  $f_{{\tt DCLK}}$  is the  ${\tt DCLK}$  frequency the system is operating.
- (6) If nSTATUS is monitored, follow the t<sub>ST2CK</sub> specification. If nSTATUS is not monitored, follow the t<sub>CF2CK</sub> specification.

## **Active Serial Configuration Timing**

Table 52 lists the DCLK frequency specification in the AS configuration scheme.

Table 52.	DCLK Frequency	Specification in the <i>l</i>	AS Configuration Scheme	(1), (2)
-----------	----------------	-------------------------------	-------------------------	----------

Minimum	Typical	Maximum	Unit
5.3	7.9	12.5	MHz
10.6	15.7	25.0	MHz
21.3	31.4	50.0	MHz
42.6	62.9	100.0	MHz

#### Notes to Table 52:

(1) This applies to the DCLK frequency specification when using the internal oscillator as the configuration clock source.

(2) The AS multi-device configuration scheme does not support DCLK frequency of 100 MHz.

Figure 14 shows the single-device configuration setup for an AS ×1 mode.





#### Notes to Figure 14:

- (1) If you are using AS  $\times 4$  mode, this signal represents the AS\_DATA[3..0] and EPCQ sends in 4-bits of data for each DCLK cycle.
- (2) The initialization clock can be from internal oscillator or CLKUSR pin.
- (3) After the option bit to enable the INIT\_DONE pin is configured into the device, the INIT\_DONE goes low.

Table 53 lists the timing parameters for AS  $\times 1$  and AS  $\times 4$  configurations in Stratix V devices.

Symbol	Parameter	Minimum	Maximum	Units
t <sub>CO</sub>	DCLK falling edge to AS_DATA0/ASDO output	—	2	ns
t <sub>SU</sub>	Data setup time before falling edge on DCLK	1.5	—	ns
t <sub>H</sub>	Data hold time after falling edge on DCLK	0	—	ns

Symbol	Parameter	Minimum	Maximum	Units
t <sub>CD2UM</sub>	CONF_DONE high to user mode $(3)$	175	437	μS
t <sub>CD2CU</sub>	CONF_DONE high to CLKUSR enabled	4 × maximum DCLK period	_	—
t <sub>CD2UMC</sub>	CONF_DONE high to user mode with CLKUSR option on	t <sub>cd2cu</sub> + (8576 × clkusr period)	_	—

Table 53. AS Timing Parameters for AS  $\times$ 1 and AS  $\times$ 4 Configurations in Stratix V Devices <sup>(1), (2)</sup> (Part 2 of 2)

#### Notes to Table 53:

(1) The minimum and maximum numbers apply only if you choose the internal oscillator as the clock source for initializing the device.

(2) t<sub>CF2CD</sub>, t<sub>CF2ST0</sub>, t<sub>CF2ST0</sub>, t<sub>CF6</sub>, t<sub>STATUS</sub>, and t<sub>CF2ST1</sub> timing parameters are identical to the timing parameters for PS mode listed in Table 54 on page 63.

(3) To enable the CLKUSR pin as the initialization clock source and to obtain the maximum frequency specification on this pin, refer to the Initialization section of the "Configuration, Design Security, and Remote System Upgrades in Stratix V Devices" chapter.

## **Passive Serial Configuration Timing**

Figure 15 shows the timing waveform for a passive serial (PS) configuration when using a MAX II device, MAX V device, or microprocessor as an external host.

Figure 15. PS Configuration Timing Waveform <sup>(1)</sup>



#### Notes to Figure 15:

- (1) The beginning of this waveform shows the device in user mode. In user mode, nCONFIG, nSTATUS, and CONF\_DONE are at logic high levels. When nCONFIG is pulled low, a reconfiguration cycle begins.
- (2) After power-up, the Stratix V device holds <code>nSTATUS</code> low for the time of the POR delay.
- (3) After power-up, before and during configuration, CONF DONE is low.
- (4) Do not leave DCLK floating after configuration. You can drive it high or low, whichever is more convenient.
- (5) DATAO is available as a user I/O pin after configuration. The state of this pin depends on the dual-purpose pin settings in the **Device and Pins Option**.
- (6) To ensure a successful configuration, send the entire configuration data to the Stratix V device. CONF\_DONE is released high after the Stratix V device receives all the configuration data successfully. After CONF\_DONE goes high, send two additional falling edges on DCLK to begin initialization and enter user mode.
- (7) After the option bit to enable the INIT DONE pin is configured into the device, the INIT DONE goes low.

# **Document Revision History**

Table 61 lists the revision history for this chapter.

 Table 61. Document Revision History (Part 1 of 3)

Date	Version	Changes
June 2018	3.9	<ul> <li>Added the "Stratix V Device Overshoot Duration" figure.</li> </ul>
April 2017	3.8	<ul> <li>Added a footnote to the "High-Speed I/O Specifications for Stratix V Devices" table.</li> </ul>
		<ul> <li>Changed the minimum value for t<sub>CD2UMC</sub> in the "PS Timing Parameters for Stratix V Devices" table.</li> </ul>
		<ul> <li>Changed the condition for 100-Ω R<sub>D</sub> in the "OCT Without Calibration Resistance Tolerance Specifications for Stratix V Devices" table.</li> </ul>
		<ul> <li>Changed the minimum value for t<sub>CD2UMC</sub> in the "AS Timing Parameters for AS '1 and AS '4 Configurations in Stratix V Devices" table</li> </ul>
		<ul> <li>Changed the minimum value for t<sub>CD2UMC</sub> in the "FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is &gt;1" table.</li> </ul>
		<ul> <li>Changed the minimum value for t<sub>CD2UMC</sub> in the "FPP Timing Parameters for Stratix V Devices When the DCLK-to-DATA[] Ratio is &gt;1" table.</li> </ul>
		<ul> <li>Changed the minimum number of clock cycles value in the "Initialization Clock Source Option and the Maximum Frequency" table.</li> </ul>
June 2016	3.7	<ul> <li>Added the V<sub>ID</sub> minimum specification for LVPECL in the "Differential I/O Standard Specifications for Stratix V Devices" table</li> </ul>
		<ul> <li>Added the I<sub>OUT</sub> specification to the "Absolute Maximum Ratings for Stratix V Devices" table.</li> </ul>
December 2015	3.6	Added a footnote to the "High-Speed I/O Specifications for Stratix V Devices" table.
December 2015	3.5	<ul> <li>Changed the transmitter, receiver, and ATX PLL data rate specifications in the "Transceiver Specifications for Stratix V GX and GS Devices" table.</li> </ul>
December 2015		<ul> <li>Changed the configuration .rbf sizes in the "Uncompressed .rbf Sizes for Stratix V Devices" table.</li> </ul>
	3.4	• Changed the data rate specification for transceiver speed grade 3 in the following tables:
		<ul> <li>"Transceiver Specifications for Stratix V GX and GS Devices"</li> </ul>
		<ul> <li>"Stratix V Standard PCS Approximate Maximum Date Rate"</li> </ul>
		<ul> <li>"Stratix V 10G PCS Approximate Maximum Data Rate"</li> </ul>
July 2015		<ul> <li>Changed the conditions for reference clock rise and fall time, and added a note to the "Transceiver Specifications for Stratix V GX and GS Devices" table.</li> </ul>
		<ul> <li>Added a note to the "Minimum differential eye opening at receiver serial input pins" specification in the "Transceiver Specifications for Stratix V GX and GS Devices" table.</li> </ul>
		<ul> <li>Changed the t<sub>co</sub> maximum value in the "AS Timing Parameters for AS '1 and AS '4 Configurations in Stratix V Devices" table.</li> </ul>
		<ul> <li>Removed the CDR ppm tolerance specification from the "Transceiver Specifications for Stratix V GX and GS Devices" table.</li> </ul>

## Table 61. Document Revision History (Part 2 of 3)

Date	Version	Changes
		Added the I3YY speed grade and changed the data rates for the GX channel in Table 1.
		<ul> <li>Added the I3YY speed grade to the V<sub>CC</sub> description in Table 6.</li> </ul>
		<ul> <li>Added the I3YY speed grade to V<sub>CCHIP_L</sub>, V<sub>CCHIP_R</sub>, V<sub>CCHSSI_L</sub>, and V<sub>CCHSSI_R</sub> descriptions in Table 7.</li> </ul>
		■ Added 240-Ω to Table 11.
		Changed CDR PPM tolerance in Table 23.
		<ul> <li>Added additional max data rate for fPLL in Table 23.</li> </ul>
	3.3	<ul> <li>Added the I3YY speed grade and changed the data rates for transceiver speed grade 3 in Table 25.</li> </ul>
		<ul> <li>Added the I3YY speed grade and changed the data rates for transceiver speed grade 3 in Table 26.</li> </ul>
		Changed CDR PPM tolerance in Table 28.
		<ul> <li>Added additional max data rate for fPLL in Table 28.</li> </ul>
November 2014		Changed the mode descriptions for MLAB and M20K in Table 33.
		■ Changed the Max value of f <sub>HSCLK_OUT</sub> for the C2, C2L, I2, I2L speed grades in Table 36.
		<ul> <li>Changed the frequency ranges for C1 and C2 in Table 39.</li> </ul>
		Changed the .rbf file sizes for 5SGSD6 and 5SGSD8 in Table 47.
		<ul> <li>Added note about nSTATUS to Table 50, Table 51, Table 54.</li> </ul>
		<ul> <li>Changed the available settings in Table 58.</li> </ul>
		<ul> <li>Changed the note in "Periphery Performance".</li> </ul>
		<ul> <li>Updated the "I/O Standard Specifications" section.</li> </ul>
		<ul> <li>Updated the "Raw Binary File Size" section.</li> </ul>
		<ul> <li>Updated the receiver voltage input range in Table 22.</li> </ul>
		<ul> <li>Updated the max frequency for the LVDS clock network in Table 36.</li> </ul>
		■ Updated the DCLK note to Figure 11.
		<ul> <li>Updated Table 23 VO<sub>CM</sub> (DC Coupled) condition.</li> </ul>
		<ul> <li>Updated Table 6 and Table 7.</li> </ul>
		■ Added the DCLK specification to Table 55.
		<ul> <li>Updated the notes for Table 47.</li> </ul>
		<ul> <li>Updated the list of parameters for Table 56.</li> </ul>
November 2013	3.2	Updated Table 28
November 2013	3.1	Updated Table 33
November 2013	3.0	Updated Table 23 and Table 28
October 2013	2.9	<ul> <li>Updated the "Transceiver Characterization" section</li> </ul>
	2.8	<ul> <li>Updated Table 3, Table 12, Table 14, Table 19, Table 20, Table 23, Table 24, Table 28, Table 30, Table 31, Table 32, Table 33, Table 36, Table 39, Table 40, Table 41, Table 42, Table 47, Table 53, Table 58, and Table 59</li> </ul>
October 2013		<ul> <li>Added Figure 1 and Figure 3</li> </ul>
		<ul> <li>Added the "Transceiver Characterization" section</li> </ul>
		<ul> <li>Removed all "Preliminary" designations.</li> </ul>